AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

 (currently amended) A metal compound represented by general formula (I):

$$\mathbf{M} = \left(\begin{array}{c} \mathbf{R}^{1} \\ \mathbf{0} \\ \mathbf{0} \\ \mathbf{p}^{2} \end{array} \right) \mathbf{A} = \mathbf{M} \left(\begin{array}{c} \mathbf{R}^{3} \\ \mathbf{R}^{4} \end{array} \right)_{n} \tag{1}$$

wherein R^1 , R^2 , R^3 , and R^4 each represent an alkyl group having 1 to 4 carbon atoms; A represents an alkanediyl group having 1 to 8 carbon atoms a methylene group; M represents a lead atom, a titanium atom or a zirconium atom; and n represents 2 when M is a lead atom or 4 when M is a titanium or zirconium atom.

- 2. (canceled)
- 3. (canceled)
- 4. (currently amended) The metal compound according to claim 1, wherein M is [[a]] the titanium atom.

- 5. (currently amended) The metal compound according to claim 1, wherein M is [[a]] the zirconium atom.
- (previously presented) A material for thin film formation comprising the metal compound according to claim 1.
- 7. (currently amended) A material for thin film formation, comprising: a metal compound of formula (I), wherein M is a lead atom;
- a compound of formula (I), wherein M is a titanium atom; and

and wherein the compound of formula (I) is the compound according to claim 1.

- 8. (currently amended) A material for thin film formation comprising the metal compound of claim [[3]] $\frac{1}{2}$, tetrakis(1-methoxy-2-methyl-2-propoxy)titanium, and tetrakis(1-methoxy-2-methyl-2-propoxy)zirconium.

vaporizing the material for thin film formation according to claim 6;[[,]]

introducing the resulting vapor containing the metal compound onto a substrate;[[,]] and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

10. (currently amended) A process for thin film formation comprising:

vaporizing a material for thin film formation containing the metal compound of claim [[3]] $\underline{1}$, to obtain vapor containing the metal $\underline{\text{compounds}}$ compound; [[,]]

introducing the resulting vapor containing the metal compounds onto a substrate;[[,]] and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

11. (currently amended) A process for thin film formation, comprising:

vaporizing a material for thin film formation containing the metal compound of claim [[3]] $\underline{1}$, a material for thin film formation containing tetrakis(1-methoxy-2-methyl-2-propoxy)titanium, and a material for thin film formation containing tetrakis(1-methoxy-2-methyl-2-propoxy)zirconium to obtain vapor containing the metal compounds; [[,]]

introducing the resulting vapor containing the metal compounds onto a substrate;[[,]] and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

12. (currently amended) A process for thin film formation comprising

vaporizing a material for thin film formation containing the metal compound of claim [[3]] $\underline{1}$, a material for thin film formation containing tetra(tert-butoxy)titanium, and a material for thin film formation containing tetra(tert-butoxy)zirconium to obtain vapor containing the metal compounds; [[,]]

introducing the resulting vapor containing the metal compounds onto a $substrate_{\ell}[[,]]$ and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

13. (currently amended) A process for thin film formation, comprising:

vaporizing a material for thin film formation containing the metal compound of claim 4, to obtain vapor containing the metal compounds; [[,]]

introducing the resulting vapor containing the metal compounds onto a $substrate_{i}[[,]]$ and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

14. (currently amended) A process for thin film formation, comprising:

vaporizing a material for thin film formation containing the metal compound of claim 5, to obtain vapor containing the metal compounds; [[,]]

introducing the resulting vapor containing the metal compounds onto a substrate;[[,]] and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

 $\label{eq:continuous} 15. \mbox{ (currently amended)} \mbox{ A process for thin film} \\ \mbox{formation, comprising:}$

vaporizing the material for thin film formation according to claim $7_L^{}[\,[\,,\,]\,]$

introducing the resulting vapor containing the metal compound onto a substrate; [[,]] and

causing the vapor to decompose and/or chemically react to form a metal-containing thin film on the substrate.

16. (currently amended) A process for thin film formation, comprising:

vaporizing the material for thin film formation according to claim \$;[[,]]

introducing the resulting vapor containing the metal compound onto a $\operatorname{substrate}_{\mathcal{E}}[[,]]$ and

 $\hbox{causing the vapor to decompose and/or chemically react}$ to form a metal-containing thin film on the substrate.} \\

- 17. (canceled)
- 18. (canceled)
- 19. (canceled)